



# TestForum 2007

Comwell Borupgaard, Copenhagen, Denmark  
November 27<sup>th</sup> & 28<sup>th</sup>, 2007

## Call for Papers / Presentations

**NTF Chairman:**  
Knut Båttstøløkken,  
Kitron

**Financial Chair:**  
Birger Schneider,  
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Nokia Siemens Networks

Jürgen Sedlacek,  
Alvetec KonTest

Tauno Jokinen,  
University of Oulu

**Sponsors of Nordic Test Forum.**



The 2 day TestForum 2007, and 8<sup>th</sup> time of this event, is a key event for Test professionals in the Nordic area and Baltic states. The event is attended by key persons in the industry as well as International providers of test and measurement equipment and solutions.

The event will take place at Comwell Borupgaard conference hotel, which is in ([http://www.comwell.com/Facts\\_and\\_facilities-4390.aspx](http://www.comwell.com/Facts_and_facilities-4390.aspx)).

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2007, which includes (but is not limited to) the following topics:

- *Embedded Test*
- *Functional test*
- *AOI / AXI*
- *Test economics*
- *ICT / Flying Probe*
- *Boundary scan test*
- *Preventive test / Prognostics*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Testing Lead Free Electronics*
- *Design to Test transfer / Design for Testing*
- *Data acquisition / collection / analysis*
- *Quality methods and tools*
- *ESD*
- *Test efficiency and optimization*
- *Future technology trends and test challenges*
- *Data acquisition / collection / analysis*

### Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practises, Emerging Ideas*, etc. You are free to submit contributions outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities and techniques rather than on particular products.

### Proceedings

At the event, Nordic Test Forum will deliver a CD-ROM of the accepted contributions whose authors wish to provide the corresponding materials.

### The Format of the Event

- The event duration will be a two-day symposium and small exhibition attached to it.
- November 26<sup>th</sup> on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each; 25 minutes of speech and 5 minutes for questions/comments.
- During the event a small exhibition will take place where exhibitors will be exhibiting their latest equipment and be available for discussions.

### Key Dates

- 1st draft proposal:
- Notification of acceptance:
- Presentation slides:

**August 31<sup>st</sup>, 2007**  
**September 28<sup>h</sup>, 2007**  
**November 16<sup>th</sup>, 2007**

### Further Information and Submissions

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Visit the NTF web page at:  
<http://www.nordicestforum.org/>

